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#### N-Channel 500V (D-S) Super Junction Power MOSFET

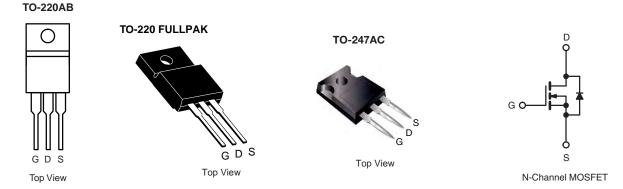
PRODUCT SUMMARY					
V <sub>DS</sub> (V) at T <sub>J</sub> max.	500				
R <sub>DS(on)</sub> max. at 25 °C (Ω)	$V_{GS} = 10 V$	0.14			
Q <sub>g</sub> max. (nC)	92				
Q <sub>gs</sub> (nC)	10				
Q <sub>gd</sub> (nC)	19				
Configuration	Single				

#### **FEATURES**

- Low figure-of-merit (FOM) Ron x Qg
- Low input capacitance (Ciss)
- Reduced switching and conduction losses
- Low gate charge (Q<sub>g</sub>)
- Avalanche energy rated (UIS)

#### **APPLICATIONS**

- Switch mode power supplies (SMPS)
- Server and telecom power supplies
- Power factor correction power supplies (PFC)



ABSOLUTE MAXIMUM RATINGS (T <sub>C</sub> :	= 25 °C, unl	less otherwis	se noted)			
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V <sub>DS</sub>	500	v	
Gate-Source Voltage			V <sub>GS</sub>	± 30	V	
Continuous Drain Current (T <sub>J</sub> = 150 °C)	V <sub>GS</sub> at 10 V	T <sub>C</sub> = 25 °C	- I <sub>D</sub>	20		
	V <sub>GS</sub> at 10 V	T <sub>C</sub> = 100 °C		12	А	
Pulsed Drain Current <sup>a</sup>			I <sub>DM</sub>	42		
Linear Derating Factor				1.4	W/°C	
Single Pulse Avalanche Energy <sup>b</sup>			E <sub>AS</sub>	204	mJ	
Maximum Power Dissipation			PD	179	W	
Operating Junction and Storage Temperature Range			T <sub>J</sub> , T <sub>stg</sub>	-55 to +150	°C	
Drain-Source Voltage Slope	$V_{DS} = 0 V t$	o 80 % V <sub>DS</sub>	d)//dt	70	V/ns	
Reverse Diode dV/dt <sup>d</sup>			dV/dt	32	v/ns	
Soldering Recommendations (Peak Temperature) <sup>c</sup>	for 10 s			300	°C	

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature.

b.  $V_{DD}$  = 50 V, starting T<sub>J</sub> = 25 °C, L = 28.2 mH, R<sub>g</sub> = 25  $\Omega$ , I<sub>AS</sub> = 3.8 A.

c. 1.6 mm from case.

d.  $I_{SD} \leq I_D, \, dI/dt = 100$  A/µs, starting  $T_J = 25 \ ^\circ C.$ 

THERMAL RESISTANCE RATINGS					
PARAMETER	SYMBOL	TYP.	MAX.	UNIT	
Maximum Junction-to-Ambient	R <sub>thJA</sub>	-	62	°C/W	
Maximum Junction-to-Case (Drain)	R <sub>thJC</sub>	-	0.7	0/10	





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<b>SPECIFICATIONS</b> ( $T_J = 25 \ ^{\circ}C$ , u	nless otherwi	se noted)					
PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static					•		
Drain-Source Breakdown Voltage	V <sub>DS</sub>	$V_{GS} = 0 V, I_{D} = 250 \mu A$		500	-	-	V
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Referenc	e to 25 °C, I <sub>D</sub> = 1 mA	-	0.59	-	V/°C
Gate-Source Threshold Voltage (N)	V <sub>GS(th)</sub>	V <sub>DS</sub> =	= V <sub>GS</sub> , I <sub>D</sub> = 250 μΑ	2.0	-	4.0	V
Gate-Source Leakage	I <sub>GSS</sub>	$V_{GS} = \pm 20 V$		-	-	± 100	nA
			$V_{GS} = \pm 30 \text{ V}$		-	± 1	μA
		V <sub>DS</sub> =	$V_{DS} = 500 \text{ V}, V_{GS} = 0 \text{ V}$		-	1	μA
Zero Gate Voltage Drain Current	IDSS	V <sub>DS</sub> = 400 \	V <sub>DS</sub> = 400 V, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 125 °C		-	10	
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 10 A	-	0.14	-	Ω
Forward Transconductance	<b>g</b> fs	V <sub>DS</sub> = 30 V, I <sub>D</sub> = 10 A		-	4.4	-	S
Dynamic				•	•	•	
Input Capacitance	C <sub>iss</sub>	$V_{GS} = 0 V,$ $V_{DS} = 100 V,$ f = 1 MHz		-	1640	-	pF
Output Capacitance	C <sub>oss</sub>			-	87	-	
Reverse Transfer Capacitance	C <sub>rss</sub>			-	6	-	
Effective Output Capacitance, Energy Related <sup>a</sup>	C <sub>o(er)</sub>	$V_{\rm DS}$ = 0 V to 400 V, $V_{\rm GS}$ = 0 V		-	73	-	
Effective Output Capacitance, Time Related <sup>b</sup>	C <sub>o(tr)</sub>			-	222	-	
Total Gate Charge	Qq			-	46	92	
Gate-Source Charge	Q <sub>gs</sub>	V <sub>GS</sub> = 10 V I <sub>D</sub> = 10 A, V <sub>DS</sub> = 400 V		-	10	-	nC
Gate-Drain Charge	Q <sub>gd</sub>			-	19	-	1
Turn-On Delay Time	t <sub>d(on)</sub>	$V_{DD} = 400 \text{ V}, \text{ I}_{D} = 10 \text{ A}, \\ V_{GS} = 10 \text{ V}, \text{ R}_{g} = 9.1 \Omega$		-	17	34	ns
Rise Time	t <sub>r</sub>			-	27	54	
Turn-Off Delay Time	t <sub>d(off)</sub>			-	48	96	
Fall Time	t <sub>f</sub>			-	25	50	
Gate Input Resistance	R <sub>g</sub>	f = 1 MHz, open drain		-	0.83	-	Ω
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	IS	MOSFET symbol showing the integral reverse p - n junction diode		-	-	20	
Pulsed Diode Forward Current	I <sub>SM</sub>			-	-	42	A
Diode Forward Voltage	V <sub>SD</sub>	T <sub>J</sub> = 25 °C, I <sub>S</sub> = 10 A, V <sub>GS</sub> = 0 V		-	-	1.2	V
Reverse Recovery Time	t <sub>rr</sub>	$T_J = 25 \text{ °C}, I_F = I_S = 10 \text{ A},$ dl/dt = 100 A/µs, V <sub>R</sub> = 25 V		-	293	-	ns
Reverse Recovery Charge	Q <sub>rr</sub>			-	4.0	-	μC
Reverse Recovery Current	I <sub>RRM</sub>			-	26	-	A

Notes

a.  $C_{oss(er)}$  is a fixed capacitance that gives the same energy as  $C_{oss}$  while  $V_{DS}$  is rising from 0 % to 80 %  $V_{DSS}$ . b.  $C_{oss(tr)}$  is a fixed capacitance that gives the same charging time as  $C_{oss}$  while  $V_{DS}$  is rising from 0 % to 80 %  $V_{DSS}$ .



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#### TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

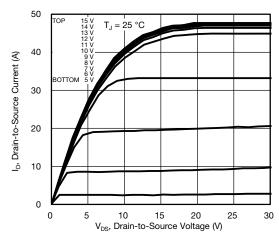


Fig. 1 - Typical Output Characteristics

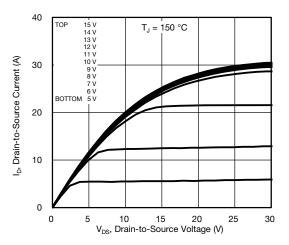


Fig. 2 - Typical Output Characteristics

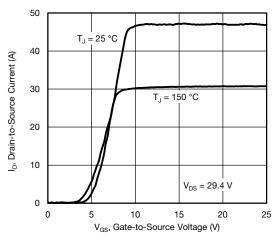


Fig. 3 - Typical Transfer Characteristics

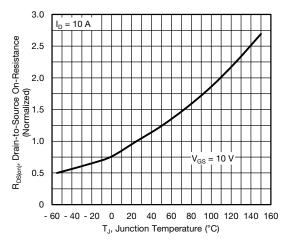


Fig. 4 - Normalized On-Resistance vs. Temperature

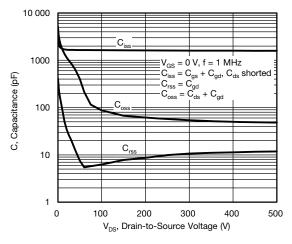


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

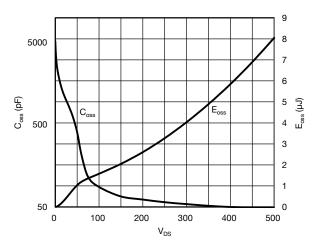


Fig. 6 -  $C_{oss}$  and  $E_{oss}$  vs.  $V_{DS}$ 



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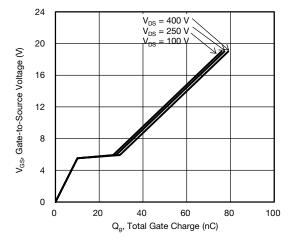


Fig. 7 - Typical Gate Charge vs. Gate-to-Source Voltage

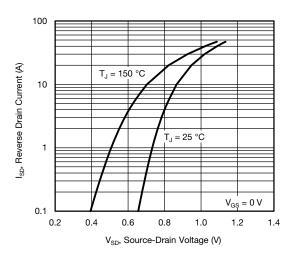


Fig. 8 - Typical Source-Drain Diode Forward Voltage

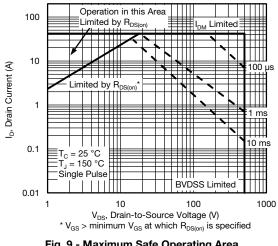


Fig. 9 - Maximum Safe Operating Area

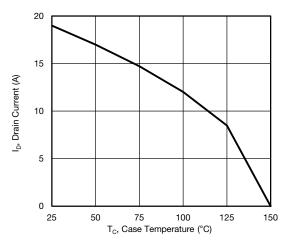


Fig. 10 - Maximum Drain Current vs. Case Temperature

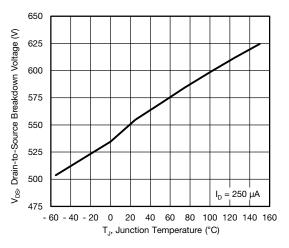
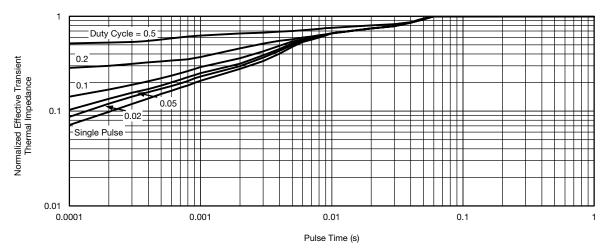


Fig. 11 - Temperature vs. Drain-to-Source Voltage



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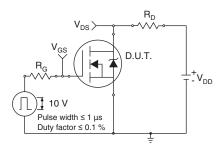


Fig. 13 - Switching Time Test Circuit

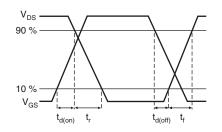


Fig. 14 - Switching Time Waveforms

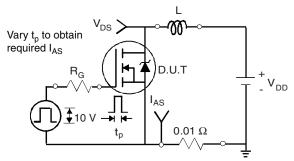


Fig. 15 - Unclamped Inductive Test Circuit

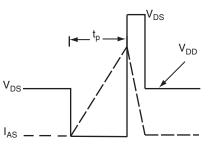


Fig. 16 - Unclamped Inductive Waveforms

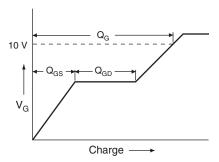


Fig. 17 - Basic Gate Charge Waveform

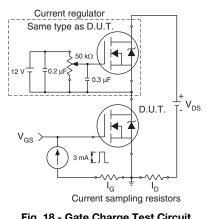
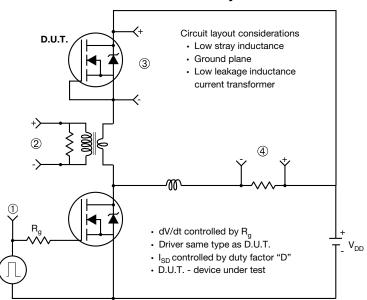
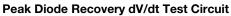


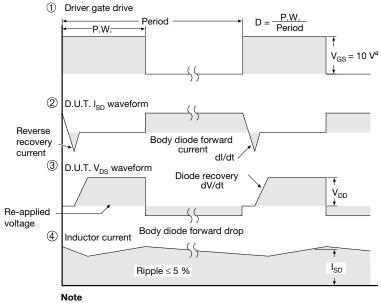
Fig. 18 - Gate Charge Test Circuit



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a.  $V_{GS} = 5$  V for logic level devices

Fig. 19 - For N-Channel



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